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8 🛛 V_{CC}

5 🛛 2A

7 🛛 1Y

6 🛛 2B

DCT PACKAGE

(TOP VIEW)

1A

GND [

1B 🛛

2Y 🗍 3

2

4

- *EPIC*TM (Enhanced-Performance Implanted CMOS) Process
- Operating Range 2-V to 5.5-V V_{CC}
- Packaged in Plastic Small-Outline Transistor Package

description

The SN74AHC2G32 is a dual 2-input positive-OR gate. The device performs the Boolean function $Y = \overline{\overline{A} \bullet \overline{B}}$ or Y = A + B in positive logic.

The SN74AHC2G32 is characterized for operation from -40°C to 85°C.

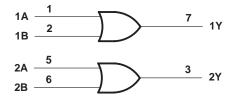
FUNCTION TABLE (each gate)								
INP	UTS	OUTPUT						
Α	В	Y						
Н	Х	Н						
Х	Н	н						
L	L	L						

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature (unless otherwise noted)[†]

Supply voltage range, V _{CC} Input voltage range, V _I (see Note 1)	
Output voltage range, V _O (see Note 1)	–0.5 V to V _{CC} + 0.5 V
Input clamp current, I _{IK} (V _I < 0)	–20 mA
Output clamp current, I_{OK} (V _O < 0 or V _O > V _{CC})	±20 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	±25 mA
Continuous current through V _{CC} or GND	±50 mA
Package thermal impedance, θ_{JA} (see Note 2)	296°C/W
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

			MIN	MAX	UNIT
VCC	Supply voltage		2	5.5	V
	V _{CC} = 2 V		1.5		
VIH	High-level input voltage	but voltage $V_{CC} = 3 V$			V
		V _{CC} = 5.5 V	3.85		
		$V_{CC} = 2 V$		0.5	
VIL	Low-level input voltage	$V_{CC} = 3 V$		0.9	V
	V _{CC} = 5.5 V			1.65	
VI	Input voltage		0	5.5	V
VO	Output voltage		0	VCC	V
	$V_{CC} = 2 V$			-50	μΑ
IOH	High-level output current	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		-4	mA
		V_{CC} = 5 V ± 0.5 V		-8	IIIA
		$V_{CC} = 2 V$		50	μΑ
IOL	Low-level output current	w-level output current $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		4	mA
		$V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$		8	IIIA
Δt/Δv	Input transition rice or fall rate	V_{CC} = 3.3 V ± 0.3 V		100	ns/V
ΔUΔV	Input transition rise or fall rate $V_{CC} = 5 V \pm 0.5 V$			20	115/ V
Тд	Operating free-air temperature		-40	85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



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	ARAMETER	TEST CONDITIONS	Vaa	T _A = 25°C			MIN	MAX	UNIT	
′	ARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX		IVIAA	UNIT	
			2 V	1.9	2		1.9			
		I _{OH} = -50 μA		2.9	3		2.9			
VOH			4.5 V	4.4	4.5		4.4		V	
		I _{OH} = -4 mA	3 V	2.58			2.48			
		I _{OH} = -8 mA	4.5 V	3.94			3.8			
		I _{OL} = 50 μA				0.1		0.1	V	
						0.1		0.1		
VOL						0.1		0.1		
		$I_{OL} = 4 \text{ mA}$	3 V			0.36		0.44		
		I _{OL} = 8 mA	4.5 V			0.36		0.44		
Ц	A or B inputs	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1	μA	
ICC		$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	5.5 V			1		10	μA	
Ci		$V_I = V_{CC}$ or GND	5 V						pF	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T _A = 25°C	MIN MAX	
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN TYP MAX		
^t PLH	A or B	V	Ci – 15 pE			ns
^t PHL	A or B	T	C _L = 15 pF			
^t PLH	A or B Y	V	Y C ₁ = 50 pF			ns
^t PHL	AUB	1	0 <u> </u>			

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

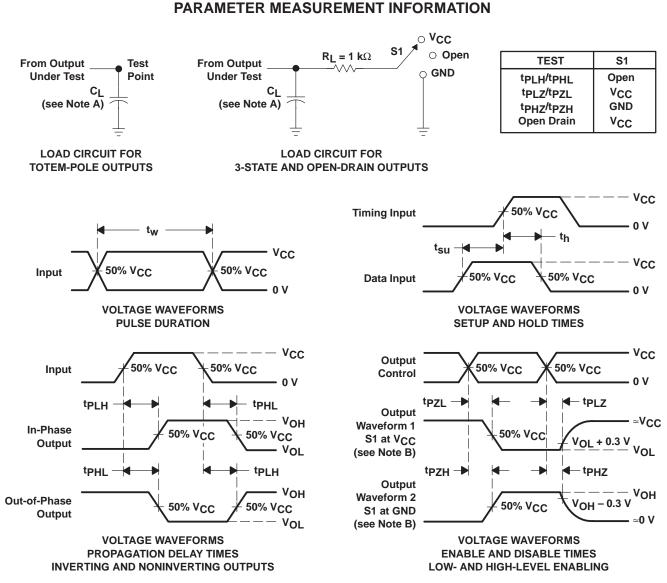
	PARAMETER	FROM	то	LOAD	T _A = 25°C				мах	UNIT	
	PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	WAX	UNIT	
	^t PLH	A or B	V	C _I = 15 pF						200	
	^t PHL	AOID	T	0L = 13 pr						ns	
	^t PLH	A or B Y	Y	V	$C_{\rm L} = 50 \rm pE$						200
Γ	^t PHL			Y C _L = 50 pF						ns	

operating characteristics, $V_{CC} = 5 V$, $T_A = 25^{\circ}C$

	PARAMETER		ONDITIONS	TYP	UNIT
Cpd	Power dissipation capacitance	No load,	f = 1 MHz		pF



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NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f \leq 3 ns, t_f \leq 3 ns.

D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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